

Search Notes

Application/Control No.

10/765,789

Examiner

John Q. Nguyen

Applicant(s)/Patent under
Reexamination

BUI ET AL.

Art Unit

3654

SEARCHED

Class	Subclass	Date	Examiner
242	333.6 333.7	2/17/2006	JN
360	74.1 74.2	2/17/2006	JN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR